

Search Notes**Application/Control No.**

10/747,620

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

HAN, JAE WON

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
205	87 103	9/6/05	KCC
205	291		
438	65-2		
	672		
	675		
	687		
	691		
	694		
	700		
	702		
438	703	9/6/05	KCC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Keyword search USPTO, USPTO-pub. EPO, JPO, Derwent TBM-TDB, Inventor search	8/30/05	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
438	652	9/7/05	KCC
	672		
	675		
	687		
	691		
	694		
	700		
	702		
438	703		
205	87		
205	103		
205	291	9/7/05	KCC